Search Notes



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225,254,256,35,34,338.33,316,259,255,245

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Application/Control No.	Applicant(s)/Patent Under Reexamination
10807188	IKEDA ET AL.
Examiner	Art Unit
Chawan, Sheela C	2624

SEARCHED					
Class	Subclass	Date	Examiner		
32	145,242	1/7/07	SCC		
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19	16,102,104,140,16,35,55,99,193,192	1/7/07	SCC		
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SEARCH NOTES					
Search Notes	Date	Examiner			
EAST, US-PGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB.	1/7/07	SCC			
INVENTOR NAME SEARCH.	1/7/07	SCC			

INTERFERENCE SEARCH					
Subclass	Date	Examine			

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